

Special issue on representative articles from 2008 Denver X-ray Conference

In early 2003, *Powder Diffraction* and the Denver X-ray Conference (DXC) agreed to a collaboration to publish representative DXC articles in the special June issue of *Powder Diffraction*. For the past six years, the annual publication of the special June issue has significantly increased the service and the number of articles available to the readers of *Powder Diffraction*, as well as the circulation of the representative DXC articles for their authors.

Articles published in this special issue were reviewed, edited, and selected by co-editors-in-chief (namely, Thomas Blanton and George Havrilla) and co-editors (John Anzelmo,

Vic Buhrke, Tim Elam, John Gilfrich, Jim Kaduk, Scott Mixture, Robert Snyder, Brian Toby, and Rene Van Grieken) of *Advances in X-ray Analysis*. I hope that our readers will find the articles appeared in this issue interesting and useful.

I also want to thank Nicole Ernst, Denise Flaherty, and Carly Bray of ICDD for making sure that everything was in order for this June publication.

Ting C. Huang
Editor-in-Chief

57th Denver X-ray Conference and selected papers for the special June issue

This special June issue of *Powder Diffraction* is comprised of selected papers presented at the 2008 57th Annual Denver X-ray Conference (DXC). At DXC 38 special sessions took place, which covered the following areas:

New Developments in XRD & XRF Instrumentation, Analysis of Nanomaterials, Cultural Heritage, Industrial Applications, X-ray Microimaging, Microbeam X-ray Analysis, Thin Films, High Temperature *In situ* Analysis, Small Angle Scattering, Fusion & Industrial Applications of XRF, Regulatory Applications, Trace Analysis and Quantitative Analysis.

As part of the Denver X-ray Conference, proceedings are published and from these proceedings selected papers covering both XRD and XRF were chosen for publication in *Powder Diffraction*. This issue of *Powder Diffraction*

will provide the reader with the opportunity to learn about current issues in a variety of materials characterization applications.

The talents of many people are required to make this special issue possible. Besides the authors themselves, we want to thank the manuscript reviewers and the staff of *Powder Diffraction*, particularly the managing editor Nicole Ernst as well as the DXC conference coordinator Denise Flaherty for all of their hard work in making this publication a reality. We hope you enjoy this publication and we look forward to seeing you at the 2009 Denver X-ray Conference in Colorado Springs, Colorado 27–31 July 2009.

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